

74VHC573FT

1. Functional Description

- Octal D-Type Latch with 3-State Outputs

2. General

The 74VHC573FT is an advanced high speed CMOS OCTAL LATCH with 3-STATE OUTPUT fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This 8-bit D-type latch is controlled by a latch enable input (LE) and an output enable input ($\overline{OE}$).

When the $\overline{OE}$ input is high, the eight outputs are in a high impedance state.

An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up.

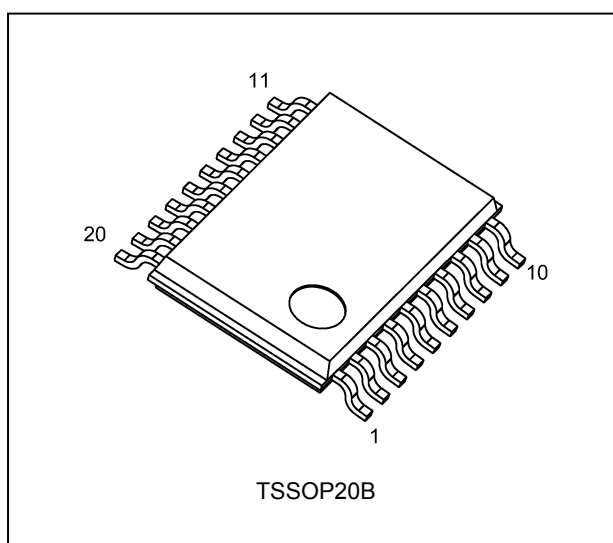
This circuit prevents device destruction due to mismatched supply and input voltages.

3. Features

- (1) AEC-Q100 (Rev. H) (Note 1)
- (2) Wide operating temperature range: $T_{opr} = -40$ to 125°C
- (3) High speed: $t_{pd} = 4.5$ ns (typ.) at $V_{CC} = 5.0$ V
- (4) Low power dissipation: $I_{CC} = 4.0$ μA (max) at $T_a = 25^{\circ}\text{C}$
- (5) High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min)
- (6) Power-down protection is provided on all inputs.
- (7) Balanced propagation delays: $t_{PLH} \approx t_{PHL}$
- (8) Wide operating voltage range: $V_{CC(opr)} = 2.0$ V to 5.5 V
- (9) Low noise: $V_{OLP} = 1.0$ V (max)
- (10) Pin and function compatible with the 74 series
(74AC/HC/AHC/LV etc.) 573 type.

Note 1: This device is compliant with the reliability requirements of AEC-Q100. For details, contact your Toshiba sales representative.

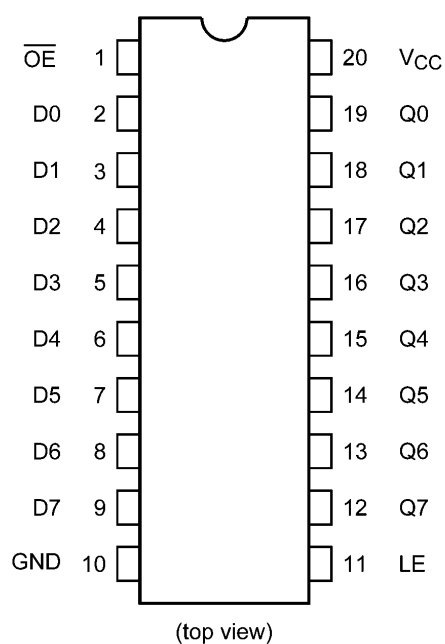
4. Packaging



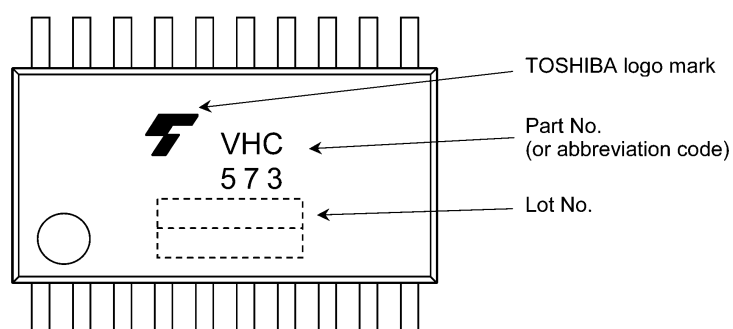
Start of commercial production

2013-03

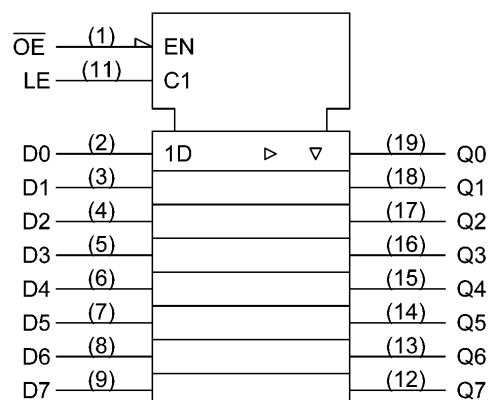
5. Pin Assignment



6. Marking



7. IEC Logic Symbol



8. Truth Table

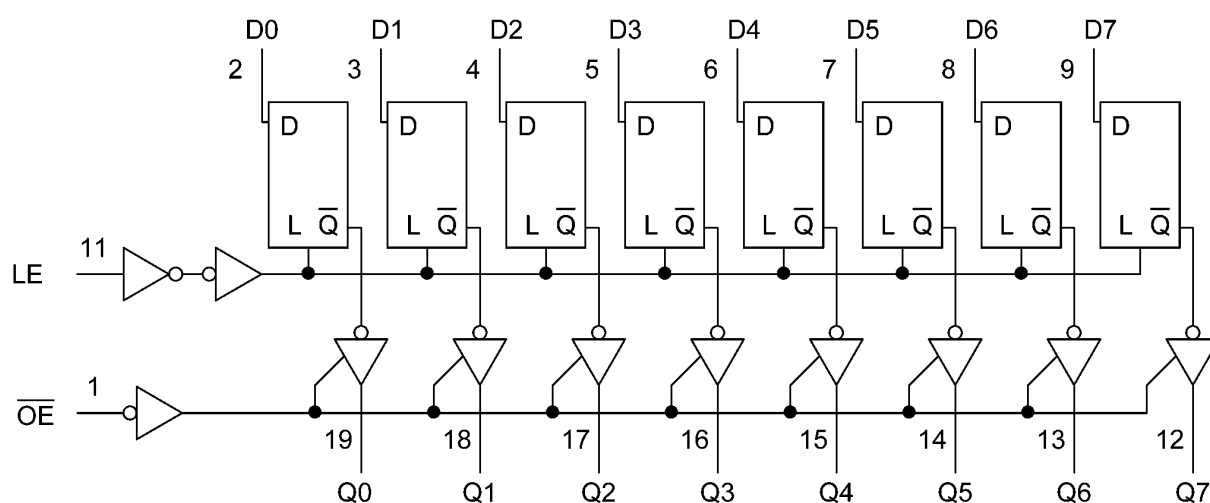
INPUT $\overline{OE}$	INPUT LE	INPUT D	OUTPUT
H	X	X	Z
L	L	X	Qn
L	H	L	L
L	H	H	H

X: Don't care

Z: High impedance

Qn: Q outputs are latched at the time when the LE input is taken to low logic level.

9. System Diagram



10. Absolute Maximum Ratings (Note)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	V_{CC}		-0.5 to 7.0	V
Input voltage	V_{IN}		-0.5 to 7.0	V
Output voltage	V_{OUT}		-0.5 to $V_{CC} + 0.5$	V
Input diode current	I_{IK}		-20	mA
Output diode current	I_{OK}		± 20	mA
Output current	I_{OUT}		± 25	mA
V_{CC} /ground current	I_{CC}		± 75	mA
Power dissipation	P_D	(Note 1)	180	mW
Storage temperature	T_{stg}		-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: 180 mW in the range of $T_a = -40$ to 85 °C. From $T_a = 85$ to 125 °C a derating factor of -3.25 mW/°C shall be applied until 50 mW.

11. Operating Ranges (Note)

Characteristics	Symbol	Test Condition	Rating	Unit
Supply voltage	V_{CC}		2.0 to 5.5	V
Input voltage	V_{IN}		0 to 5.5	V
Output voltage	V_{OUT}		0 to V_{CC}	V
Operating temperature	T_{opr}		-40 to 125	°C
Input rise and fall times	dt/dv	$V_{CC} = 3.3 \pm 0.3$ V	0 to 100	ns/V
		$V_{CC} = 5.0 \pm 0.5$ V	0 to 20	

Note: The operating ranges must be maintained to ensure the normal operation of the device.

Unused inputs and bus inputs must be tied to either V_{CC} or GND.

12. Electrical Characteristics

12.1. DC Characteristics (Unless otherwise specified, $T_a = 25\text{ }^{\circ}\text{C}$)

Characteristics	Symbol	Test Condition		V_{CC} (V)	Min	Typ.	Max	Unit
High-level input voltage	V_{IH}	—		2.0	1.50	—	—	V
				3.0 to 5.5	$V_{CC} \times 0.7$	—	—	
Low-level input voltage	V_{IL}	—		2.0	—	—	0.50	V
				3.0 to 5.5	—	—	$V_{CC} \times 0.3$	
High-level output voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -50\text{ }\mu\text{A}$	2.0	1.9	2.0	—	V
				3.0	2.9	3.0	—	
				4.5	4.4	4.5	—	
			$I_{OH} = -4\text{ mA}$	3.0	2.58	—	—	
			$I_{OH} = -8\text{ mA}$	4.5	3.94	—	—	
Low-level output voltage	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 50\text{ }\mu\text{A}$	2.0	—	0.0	0.1	V
				3.0	—	0.0	0.1	
				4.5	—	0.0	0.1	
			$I_{OL} = 4\text{ mA}$	3.0	—	—	0.36	
			$I_{OL} = 8\text{ mA}$	4.5	—	—	0.36	
3-state output OFF-state leakage current	I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = V_{CC}$ or GND		5.5	—	—	± 0.25	μA
Input leakage current	I_{IN}	$V_{IN} = 5.5\text{ V}$ or GND		0 to 5.5	—	—	± 0.1	
Quiescent supply current	I_{CC}	$V_{IN} = V_{CC}$ or GND		5.5	—	—	4.0	

12.2. DC Characteristics (Unless otherwise specified, $T_a = -40\text{ to }85\text{ }^{\circ}\text{C}$)

Characteristics	Symbol	Test Condition		V_{CC} (V)	Min	Max	Unit
High-level input voltage	V_{IH}	—		2.0	1.50	—	V
				3.0 to 5.5	$V_{CC} \times 0.7$	—	
Low-level input voltage	V_{IL}	—		2.0	—	0.50	V
				3.0 to 5.5	—	$V_{CC} \times 0.3$	
High-level output voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -50\text{ }\mu\text{A}$	2.0	1.9	—	V
				3.0	2.9	—	
				4.5	4.4	—	
			$I_{OH} = -4\text{ mA}$	3.0	2.48	—	
			$I_{OH} = -8\text{ mA}$	4.5	3.80	—	
Low-level output voltage	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 50\text{ }\mu\text{A}$	2.0	—	0.1	V
				3.0	—	0.1	
				4.5	—	0.1	
			$I_{OL} = 4\text{ mA}$	3.0	—	0.44	
			$I_{OL} = 8\text{ mA}$	4.5	—	0.44	
3-state output OFF-state leakage current	I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = V_{CC}$ or GND		5.5	—	± 2.50	μA
Input leakage current	I_{IN}	$V_{IN} = 5.5\text{ V}$ or GND		0 to 5.5	—	± 1.0	
Quiescent supply current	I_{CC}	$V_{IN} = V_{CC}$ or GND		5.5	—	40.0	

12.3. DC Characteristics (Unless otherwise specified, $T_a = -40$ to $125\text{ }^{\circ}\text{C}$)

Characteristics	Symbol	Test Condition		V_{CC} (V)	Min	Max	Unit
High-level input voltage	V_{IH}	—		2.0	1.50	—	V
				3.0 to 5.5	$V_{CC} \times 0.7$	—	
Low-level input voltage	V_{IL}	—		2.0	—	0.50	V
				3.0 to 5.5	—	$V_{CC} \times 0.3$	
High-level output voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -50\text{ }\mu\text{A}$	2.0	1.9	—	V
				3.0	2.9	—	
				4.5	4.4	—	
			$I_{OH} = -4\text{ mA}$	3.0	2.40	—	
			$I_{OH} = -8\text{ mA}$	4.5	3.70	—	
Low-level output voltage	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 50\text{ }\mu\text{A}$	2.0	—	0.1	V
				3.0	—	0.1	
				4.5	—	0.1	
			$I_{OL} = 4\text{ mA}$	3.0	—	0.55	
			$I_{OL} = 8\text{ mA}$	4.5	—	0.55	
3-state output OFF-state leakage current	I_{OZ}	$V_{IN} = V_{IH}$ or V_{IL} $V_{OUT} = V_{CC}$ or GND		5.5	—	± 10.0	μA
Input leakage current	I_{IN}	$V_{IN} = 5.5\text{ V}$ or GND		0 to 5.5	—	± 2.0	μA
Quiescent supply current	I_{CC}	$V_{IN} = V_{CC}$ or GND		5.5	—	80.0	μA

12.4. Timing Requirements (Unless otherwise specified, $T_a = 25^\circ\text{C}$, Input: $t_r = t_f = 3\text{ ns}$)

Characteristics	Symbol	Test Condition	V_{CC} (V)	Limit	Unit
Minimum pulse width (LE)	$t_{w(H)}$	—	3.3 ± 0.3	5.0	ns
			5.0 ± 0.5	5.0	ns
Minimum setup time	t_s	—	3.3 ± 0.3	3.5	ns
			5.0 ± 0.5	3.5	ns
Minimum hold time	t_h	—	3.3 ± 0.3	1.5	ns
			5.0 ± 0.5	1.5	ns

12.5. Timing Requirements (Unless otherwise specified, $T_a = -40$ to 85°C , Input: $t_r = t_f = 3\text{ ns}$)

Characteristics	Symbol	Test Condition	V_{CC} (V)	Limit	Unit
Minimum pulse width (LE)	$t_{w(H)}$	—	3.3 ± 0.3	5.0	ns
			5.0 ± 0.5	5.0	
Minimum setup time	t_s	—	3.3 ± 0.3	3.5	ns
			5.0 ± 0.5	3.5	
Minimum hold time	t_h	—	3.3 ± 0.3	1.5	ns
			5.0 ± 0.5	1.5	

12.6. Timing Requirements (Unless otherwise specified, $T_a = -40$ to 125°C , Input: $t_r = t_f = 3\text{ ns}$)

Characteristics	Symbol	Test Condition	V_{CC} (V)	Limit	Unit
Minimum pulse width (LE)	$t_{w(H)}$	—	3.3 ± 0.3	5.0	ns
			5.0 ± 0.5	5.0	
Minimum setup time	t_s	—	3.3 ± 0.3	4.5	ns
			5.0 ± 0.5	4.0	
Minimum hold time	t_h	—	3.3 ± 0.3	1.5	ns
			5.0 ± 0.5	1.5	

12.7. AC Characteristics (Unless otherwise specified, $T_a = 25\text{ }^\circ\text{C}$, Input: $t_r = t_f = 3\text{ ns}$)

Characteristics	Symbol	Note	Test Condition	V_{CC} (V)	C_L (pF)	Min	Typ.	Max	Unit
Propagation delay time (LE-Q)	t_{PLH}, t_{PHL}		—	3.3 ± 0.3	15	—	7.6	11.9	ns
					50	—	10.1	15.4	
				5.0 ± 0.5	15	—	5.0	7.7	
					50	—	6.5	9.7	
Propagation delay time (D-Q)	t_{PLH}, t_{PHL}		—	3.3 ± 0.3	15	—	7.0	11.0	ns
					50	—	9.5	14.5	
				5.0 ± 0.5	15	—	4.5	6.8	
					50	—	6.0	8.8	
3-state output enable time	t_{PZL}, t_{PZH}		$R_L = 1\text{ k}\Omega$	3.3 ± 0.3	15	—	7.3	11.5	ns
					50	—	9.8	15.0	
				5.0 ± 0.5	15	—	5.2	7.7	
					50	—	6.7	9.7	
3-state output disable time	t_{PLZ}, t_{PHZ}		$R_L = 1\text{ k}\Omega$	3.3 ± 0.3	50	—	10.7	14.5	ns
				5.0 ± 0.5	50	—	6.7	9.7	
Output skew	t_{osLH}, t_{osHL}	(Note 1)	—	3.3 ± 0.3	50	—	—	1.5	ns
				5.0 ± 0.5	50	—	—	1.0	
Input capacitance	C_{IN}		—			—	4	10	pF
Output capacitance	C_{OUT}		—			—	6	—	pF
Power dissipation capacitance	C_{PD}	(Note 2)	—			—	29	—	pF

Note 1: Parameter guaranteed by design. ($t_{osLH} = |t_{PLHM} - t_{PLHN}|$, $t_{osHL} = |t_{PHLM} - t_{PHLN}|$)

Note 2: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.

$$I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8 \text{ (per latch)}$$

And the total C_{PD} when n pcs. of latch operate can be gained by the following equation.

$$C_{PD} \text{ (total)} = 21 + 8 \times n$$

12.8. AC Characteristics (Unless otherwise specified, $T_a = -40\text{ to }85\text{ }^\circ\text{C}$, Input: $t_r = t_f = 3\text{ ns}$)

Characteristics	Symbol	Note	Test Condition	V_{CC} (V)	C_L (pF)	Min	Max	Unit
Propagation delay time (LE-Q)	t_{PLH}, t_{PHL}		—	3.3 ± 0.3	15	1.0	14.0	ns
					50	1.0	17.5	
				5.0 ± 0.5	15	1.0	9.0	
					50	1.0	11.0	
Propagation delay time (D-Q)	t_{PLH}, t_{PHL}		—	3.3 ± 0.3	15	1.0	13.0	ns
					50	1.0	16.5	
				5.0 ± 0.5	15	1.0	8.0	
					50	1.0	10.0	
3-state output enable time	t_{PZL}, t_{PZH}		$R_L = 1\text{ k}\Omega$	3.3 ± 0.3	15	1.0	13.5	ns
					50	1.0	17.0	
				5.0 ± 0.5	15	1.0	9.0	
					50	1.0	11.0	
3-state output disable time	t_{PLZ}, t_{PHZ}		$R_L = 1\text{ k}\Omega$	3.3 ± 0.3	50	1.0	16.5	ns
				5.0 ± 0.5	50	1.0	11.0	
Output skew	t_{osLH}, t_{osHL}	(Note 1)	—	3.3 ± 0.3	50	—	1.5	ns
				5.0 ± 0.5	50	—	1.0	ns
Input capacitance	C_{IN}		—			—	10	pF

Note 1: Parameter guaranteed by design. ($t_{osLH} = |t_{PLHM} - t_{PLHN}|$, $t_{osHL} = |t_{PHLM} - t_{PHLN}|$)

(Unless otherwise specified, $T_a = -40$ to $125\text{ }^{\circ}\text{C}$, Input: $t_r = t_f = 3\text{ ns}$)

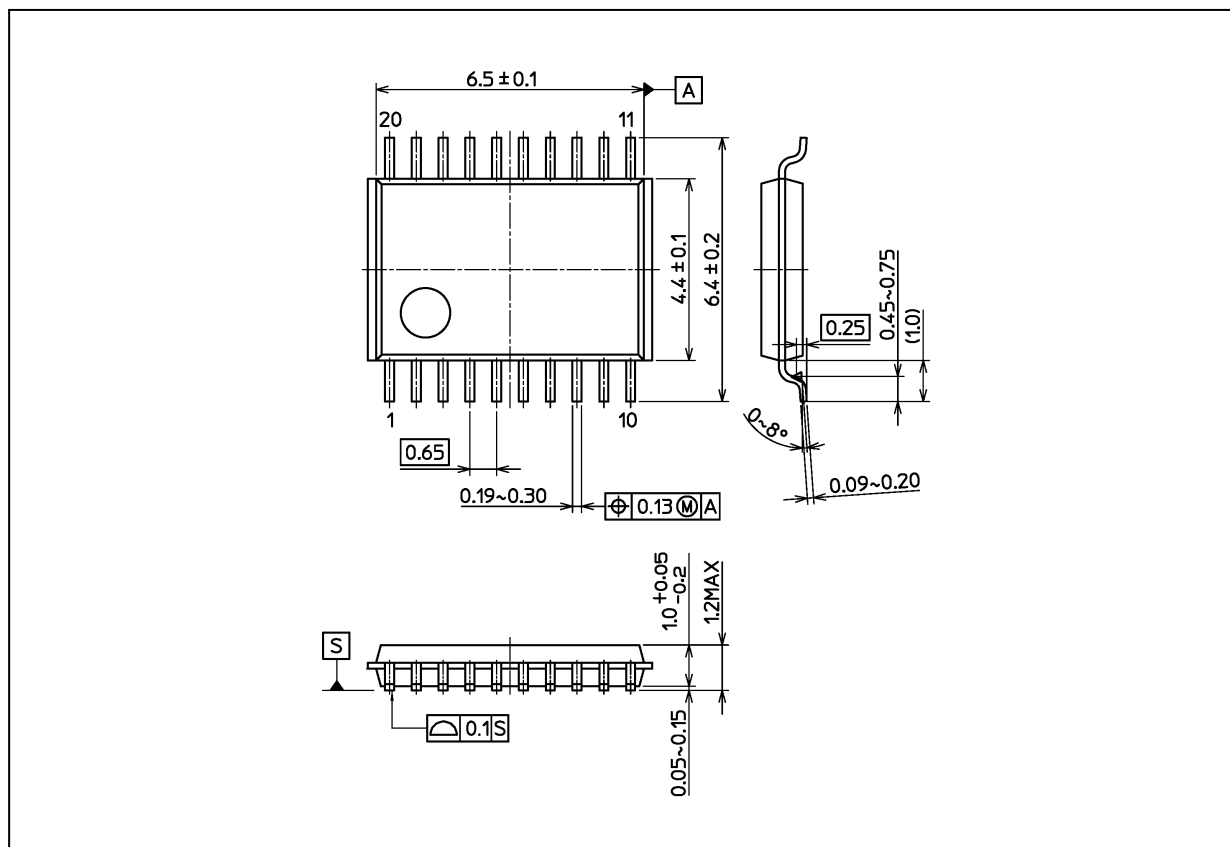
Note 1: Parameter guaranteed by design. ($t_{\text{osLH}} = |t_{\text{PLHm}} - t_{\text{PLHn}}|$, $t_{\text{osHL}} = |t_{\text{PHLm}} - t_{\text{PHLn}}|$)

Characteristics	Symbol	Test Condition	V _{CC} (V)	Typ.	Limit	Unit
Quiet output maximum dynamic V _{OL}	V _{OLP}	C _L = 50 pF	5.0	0.8	1.0	V
Quiet output minimum dynamic V _{OL}	V _{OLV}	C _L = 50 pF	5.0	-0.8	-1.0	
Minimum high-level dynamic input voltage	V _{IHD}	C _L = 50 pF	5.0	—	3.5	
Maximum low-level dynamic input voltage	V _{ILD}	C _L = 50 pF	5.0	—	1.5	

The diagram shows a CMOS inverter circuit. The input node is connected to a square symbol labeled "Input". This node is connected to the gates of both an NMOS transistor (bottom) and a PMOS transistor (top). The NMOS transistor's source is connected to ground, and its drain is connected to the output node. The PMOS transistor's source is connected to ground, and its drain is connected to the output node. The output node is connected to a switch symbol. The circuit is labeled with "Input" and "Output" nodes.

Package Dimensions

Unit: mm



Weight: 0.071 g (typ.)

Package Name(s)
Nickname: TSSOP20B

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